UNS
UNIVERSIDAD NACIONAL DEL SUR

TECHNICAL SERVICE

Microscopy

STRUCTURAL AND MORPHOLOGICAL ANALYSIS OF MATERIALS

KEY WORDS

MICROSCOPIC ANALYSIS, MORPHOLOGY, MICROSTRUCTURE

DESCRIPTION

Optical, electron (SEM, TEM) and atomic force microscopy (AFM) can be used to study the microstructure, morphology, particle size, and defects of materials in micrometric and nanometric scale.

AVAILABLE TECHNIQUES AND/OR EQUIPMENT

- Optical Microscope, reflection, transmission and polarized light modes with a hot stage
- Scanning Electron Microscope coupled to an auxiliary Energy Dispersive X-ray Spectroscopy detector
- Transmission Electron Microscope
- Atomic Force Microscope

APPLICATIONS

- Nanoparticles
- Thin polymeric films and multilayer laminates
- Coatings
- Composites and nanocomposites
- Voids, cracks and defects
- Crystalline structure

CONTACT US

ott@plapiqui.edu.ar

Universidad Nacional del Sur